Express Mail Label No.: EV 434014702 US Attorney Docket No.: D5116-00002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Sharad Saxena et al.

Serial No.: 09/675,427

Group Art Unit: 2128

Filed: September 29, 2000

Examiner: Morella Rosales Hanner

For: AN EFFICIENT METHOD FOR MODELING AND SIMULATION OF THE IMPACT OF LOCAL AND GLOBAL VARIATION OF INTEGRATED CIRCUITS

I hereby certify that this correspondence is being deposited with the United States Postal Service on the date shown below with sufficient postage as "Express Mail Post Office to Addressee" Mailing Label Number **EV434014702US** to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

August 23, 200

Steven E. Koffs, Registration No. 37,163

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

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AUG 2 7 2004

Dear Sir:

Technology Center 2100

Enclosed herewith is an Supplemental Information Disclosure Statement pursuant to 37 CFR. § 1.56 in connection with the above-identified application, which statement is being filed:

- [] Together with the present application.
- [] Before the first Office Action on the merits or three (3) months from the filing date of this application, whichever occurs last. [37 CFR § 1.97(b)]
- [X] After the first Office Action on the merits, but before a Final Office Action under §1.113 or Notice of Allowance under §1.311, whichever occurs first. [37 CFR § 1.97(c)]
- [] After a Final Office Action under §1.113 or Notice of Allowance under §1.311, but prior to or with payment of the Issue Fee. [37 CFR § 1.97(d)]

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	Cons	istent v	vith Applicant's obligations pursuan	t to 37 CFR §§1.97 and 1.98, the				
follow	ing red	quireme	ents have been met:					
	[]	No se	eparate requirements are needed.					
	[]	No ac	dditional fee is required.					
[X]	Fee Under 37 CFR § 1.97(c)							
			ee of <u>\$180.00</u> for submission of an 7(p) accompanies this statement.	IDS under § 1.97(c) as set forth in				
[]	Fee l	<u>Jnder (</u>	37 CFR § 1.97(d)					
			ee of \$180.00 for submission of an r § 1.97(d) set forth in § 1.17(p) acc					
[]	Certification Under 37 CFR § 1.97(e)							
		()	Each item of information containe communication from a foreign pat application not more than three m statement; or	ent office in a counterpart foreign				
		()	No item of information contained in communication from a foreign pat application, and, to the knowledge statement after making reasonable contained in this statement was kin §1.56(c) more than three month statement.	ent office in a counterpart foreign of the person signing the le inquiry, no item of information nown to any individual designated				
Prov	ision (of Cop	ies of References					
[]	Copie	es of cit	ted references which are U.S. Pate	nts or U.S. Patent Application				
	Publications are not required for this application, which has a filing date after							
	June 30, 2003 (1276 OG 55, 5 August 2003).							
[X]	A copy of each of the references listed on the attached Form PTO-1449 is							
	enclo	sed he	rewith and forms a part hereof.					
	[]		al Translations of References a part hereof.	are enclosed herewith and				

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[]	A copy of the European Search Report from a corresponding or related
	EPO application is enclosed herewith.

[] A copy of the International Search Report from a corresponding or related PCT application is enclosed herewith.

Identification of Prior Application(s) In Which Listed Information Was Already Cited And For Which No Copies Are Submitted Or Need Be Submitted

- [] This application relies, under 35 U.S.C. § 120, on the earlier filing date of prior U.S. Application No(s).

 The following references were submitted to, and/or cited by, the Office in the prior application(s) and therefore are not required to be provided in this application:
- [x] The Commissioner is hereby authorized to charge any fees associated with this communication or credit any overpayment to Deposit Account No. <u>04-1679</u>. A duplicate copy of this transmittal is attached.

Respectfully submitted,

Registration No. 37,163 Attorney for Applicant(s)

Steven E. Koffs

DATE: 8 23 04

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Fax: 215-979-1020

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PTO/SB/08B (08-03)
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Substitute fo	or form 1449/PTO			Complete if Known RECEIVED		
y Cabbillato IC	31 101111 144011 10			Application Number	09/675,427	
INFO	RMATION	DIS	CLOSURE	Filing Date	September 29, 2000	JG 2 7 2004
STAT	EMENT B	Y A	PPLICANT	First Named Inventor	Sharad Saxena Techno	logy Center 210
(Use as many sheets as necessary)				Art Unit	2128	-3,
	(USB as many sne	865 d5 f1	ecessary)	Examiner Name	Morella I Rosales Hanner	
Sheet 1		of	2	Attorney Docket Number	D5116-00002	

		NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
	-	Y. CHENG et al., "MOSFET Modeling and BSIM User Guide." Kluwer Academic Publishers, Boston, 1999	<i>"</i>		
		CONTI et al. "Parametric Yield Formulation of MOS IC's Affected by Mismatch Effect." IEEE Transactions on Computer-Aided Design, Vol. 18, pp. 582-596, May 1999			
		GUARDIANI et al., "Applying a submicron mismatch model to practical IC design." IEEE Custom Integrated Circuits Conference, San Diego (CA), May 1994			
		HUIJSING et al., "Low-Power Low-Voltage VLSI Operational Amplifier Cells." IEEE Transactions on Circuits and Systems-I: Fundamental Theory and Applications, Vol. 42, No. 11, pp. 841-852, November 1995			
		HWANG, et al., "Universal Constant-gm Input-Stage Architectures for Low-Voltage Op Amps." IEEE Transactions on Circuits and Systems-I: Fundamental Theory and Applications, Vol. 42, No. 11, pp. 886-894, November 1995.			
		PINEDA DE GYVEZ et al., "Integrated Circuits Manufacturability: the Art of Process and Design Integration." pp. 158-166, IEEE Press, New York, 1999			
		FELT et al., "Hierarchical Statistical Characterization of Mixed-Signal Circuits Using Behavioral Modeling." IEEE-ACM International Conference on Computer Aided Design, San Jose (CA), November 1996			
		MICHAEL et al., "Statistical Modeling for Computer-Aided Design of MOS VLSI Circuits." Kluwer Academic Publishers, Boston, 1993			
		MICHAEL et al., "Statistical Modeling of Device Mismatch for Analog Integrated Circuits." IEEE Journal of Solid-State Circuits, Vol. 27, No. 2, February 1992			
		"pdPCA User's Manual." Version ?, PDF Solutions, Inc., San Jose, 1998			

Examiner	Date	
Signature	 Considered	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached. This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO:

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	te for form 1449/PTO			Complete if Known		
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INF	ORMATION	DIS	CLOSURE	Filing Date	September 29, 2000	
STA	TEMENT E	BY A	PPLICANT	First Named Inventor	Sharad Saxena	
	// to a community			Art Unit	2128	
	(Use as many she	eus as n	ecessary)	Examiner Name	Morella i Rosales Hanner	
Sheet	2	of	2	Attorney Docket Number	D5116-00002	

		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		PELGROM et al., "Matching Properties of MOS Transistors." IEEE Journal of Solid-State Circuits, Vol. 24, No. 5, SC-24, pp. 1433-1440, October 1989	
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		Technology Center 2100	

Examiner	Date	
Signature	 Considered	

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1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

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